Notice of Allowability	Application No.		
	09/512,570		
	Examiner	Art Unit	
	Tom Y Lu	2621	
The MAILING DATE of this communication appeal all claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R	(OR REMAINS) CLOSED or other appropriate comm IGHTS. This application is	in this application. If not included nunication will be mailed in due course	e initiative
1. This communication is responsive to the amendment filed	on 07/21/2004.		
2. ⊠ The allowed claim(s) is/are <u>1,2,4-7,9-12 and 14-21</u> .			
3. $igotimes$ The drawings filed on <u>24 February 2004</u> are accepted by the	he Examiner.		
4. Acknowledgment is made of a claim for foreign priority ur a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority do International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give 6. CORRECTED DRAWINGS (as "replacement sheets") mus (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1	e been received. e been received in Application cuments have been received of this communication to fil fENT of this application. litted. Note the attached EX es reason(s) why the oath of st be submitted. Son's Patent Drawing Reviews as Amendment / Comment of	on Noed in this national stage application from the stage applicatio	ents E OF
each sheet. Replacement sheet(s) should be labeled as such in to a sheet of the deposition of the depo	he header according to 37 C sit of BIOLOGICAL MAT	FR 1.121(d). ERIAL must be submitted. Note th	
Attachment(s)			
 Notice of References Cited (PTO-892) D Notice of Draftperson's Patent Drawing Review (PTO-948) 		nformal Patent Application (PTO-152)	
	Paper No.	Summary (PTO-413), /Mail Date	
 Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 		Amendment/Comment	
4. Examiner's Comment Regarding Requirement for Deposit		Statement of Reasons for Allowance	
of Biological Material		LEO BOUDREAU PERVISORY PATENT EXAMINER	`
LLS Patent and Trademark Office		TECHNOLOGY CENTER 2600	

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DETAILED ACTION

Response to Amendment

- 1. The Request for Continued Examination filed on July 21, 2004 has been entered.
- 2. Upon entry of the Request for Continued Examination, the amendment filed on July 21, 2004 has been entered.
- 3. Claims 3, 8 and 13 were cancelled.
- 4. Claims 1, 6 and 11 are amended.
- 5. Claims 1-2, 4-7, 9-12 and 14-21 are pending.

Response to Arguments

6. Applicant's arguments, see Remarks, pages 8-12, filed on July 21, 2004, with respect to Claims 1, 6 and 11 have been fully considered and are persuasive. The rejection of Claims 1, 6 and 11 has been withdrawn.

Allowable Subject Matter

7. Claims 1-2, 4-7, 9-12 and 14-21 are allowed.

The following is an examiner's statement of reasons for allowance:

a. Independent Claims 1, 6 and 11 define features of using a photolithography process to form a submicron structure on a semiconductor wafer; forming an electron beam image of said structure on a two-dimensional array of pixels, wherein said image has a shape; identifying a more precise edge of the image shape by obtaining intensity vs. pixel information along a plurality of scans extending in different direction, through substantially a point along a preliminary, approximate edge of the image shape; detecting a point on the more precise edge

location of the image by subjecting the recognized scans to an edge detection algorithm. These features in combination with other feature in Claims 1, 6 and 11, which are the broadest allowable claims, are not taught or suggested by the art of record.

- b. Claims 2, 4-5, 16 and 17 are dependent upon Claim 1.
- c. Claims 7, 9-10, 18 and 19 are dependent upon Claim 6.
- d. Claims 12, 14-15, 20 and 21 are dependent upon Claim 11.
- 8. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

- 9. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
 - a. Tessadra, U.S. Patent Application Publication No. 2003/0095710 A1, see Paragraph 0090.
 - b. Ausschnitt et al, U.S. Patent No. 5,914,784, see abstract, figure 6, and column 6.
- 10. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tom Y Lu whose telephone number is (703) 306-4057. The examiner can normally be reached on 8:30AM-5PM.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Leo H Boudreau can be reached on (703) 305-4706. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tom Y. Lu

LEU BOUDREAU

SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600